

TENTATIVE

Notice: This is not a final specification.

Some parametric limits are subject to change

<IGBT Modules>

CM100DY-24T

HIGH POWER SWITCHING USE INSULATED TYPE

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(Date)		25 Apr. 2016		



dual switch (half-bridge)

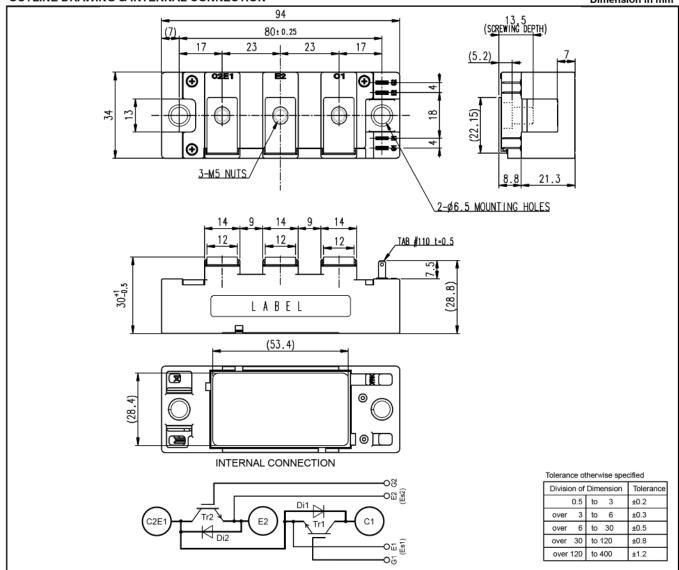
- PC-TIM applied optional
- •Copper base plate (non-plating)
- •Tin plating pin terminals
- •RoHS Directive compliant
- •Recognized under UL1557, File E323585

APPLICATION

AC Motor Control, Motion/Servo Control, Power supply, etc.

OUTLINE DRAWING & INTERNAL CONNECTION

Dimension in mm



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MAXIMUM RATINGS (Tvj=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V	
V _{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V	
lc	Collector current	DC, T _C =125 °C (Note2, 4)	100	^	
I _{CRM}	Collector current	Pulse, Repetitive (Note3)	200	1 ^	
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	1180	W	
I _E (Note1)	Emitter current	DC (Note2)	100	_	
I _{ERM} (Note1)	Emitter current	Pulse, Repetitive (Note3)	200	^	
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T _{vjmax}	Maximum junction temperature	Instantaneous event (overload)	175	°C	
T _{Cmax}	Maximum case temperature	ature (Note4)		1	
T _{vjop}	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T _{stg}	Storage temperature	-	-40 ~ +125] [

ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	Itam	Conditions		Limits			Linit
Symbol Item		Conditions		Min.	Тур.	Max.	Unit
CES	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited		-	-	1.0	mA
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circuited		-	-	0.5	μA
V _{GE(th)}	Gate-emitter threshold voltage	I _C =10 mA, V _{CE} =10 V		5.4	6.0	6.6	٧
		I _C =100 A, V _{GE} =15 V,	T _{vj} =25 °C		1.65	1.95	v
V _{CEsat} (Terminal)		Refer to the figure of test circuit	T _{vj} =125 °C		1.85	-	
	(Note5)	T _{vj} =150 °C	-	1.90	-	1	
	Collector-emitter saturation voltage	I _C =100 A,	T _{vj} =25 °C	-	1.55	1.80	
V _{CEsat}		V _{GE} =15 V,	T _{vj} =125 °C	-	1.75	-	l v
(Chip)		(Note5)	T _{vj} =150 °C	-	1.80	-	1
Cies	Input capacitance		-	-	20.5	nF	
Coes	Output capacitance	V _{CE} =10 V, G-E short-circuited		-	-		0.6
Cres	Reverse transfer capacitance			-	0.3		
Q _G	Gate charge	V _{CC} =600 V, I _C =100 A, V _{GE} =15 V		-	0.7	-	μC
t _{d(on)}	Turn-on delay time	V _{CC} =600 V, I _C =100 A, V _{GE} =±15 V, R _G =9.1 Ω, Inductive load		-	-	300	ns
tr	Rise time			-	-	150	
t _{d(off)}	Turn-off delay time			-	-	500	
t _f	Fall time			-	-	300	1
(Note 1)		I _E =100 A, G-E short-circuited,	T _{vj} =25 °C		1.70	2.10	V
V _{EC} (Note.1) (Terminal)		Refer to the figure of test circuit	T _{vj} =125 °C	-	1.85	-	
(Terriinai)	Funithar callector valters	(Note5)	T _{vj} =150 °C	-	1.85	-]
. (Nate 1)	- Emitter-collector voltage	I _E =100 A,	T _{vj} =25 °C	-	1.65	2.00	
V _{EC} (Note.1) (Chip)		G-E short-circuited,	T _{vj} =125 °C	-	1.65	-) v
(Cnip)	⊃nip)	(Note5)	T _{vj} =150 °C	-	1.65	-	1
t _{rr} (Note1)	Reverse recovery time	V _{CC} =600 V, I _E =100 A, V _{GE} =±15 V,		-	-	400	ns
Q _{rr} (Note1)	Reverse recovery charge	R_G =9.1 Ω , Inductive load		-	10	-	μC
Eon	Turn-on switching energy per pulse	V _{CC} =600 V, I _C =I _E =100 A,			12.9	-	mJ
E _{off}	Turn-off switching energy per pulse	V_{GE} =±15 V, R_G =9.1 Ω , T_{vj} =150 °C,		-	10	-	1 1113
E _{rr} (Note1)	Reverse recovery energy per pulse	Inductive load		-	6.4	-	mJ
R _{CC'+EE'}	Internal lead resistance	Main terminals-chip, per switch, T _C =25 °C (Note4)		-	0.2	-	mΩ
r _g	Internal gate resistance	Per switch		-	0	-	Ω

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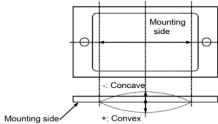
THERMAL RESISTANCE CHARACTERISTICS

Symbol Item		Conditions	Limits			Unit
		Conditions	Min.	Тур.	Max.	Offic
R _{th(j-c)Q}	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	127	K/kW
$R_{th(j-c)D}$	Thermal resistance	Junction to case, per Inverter FWD (Note4)	-	-	228	N/KVV
R _{th(c-s)} Contact the	Contact thermal resistance	Case to heat sink, Thermal grease applied (Note4, 6)	-	36.6	1	K/kW
	Contact thermal resistance	per 1 module, PC-TIM applied (Note4, 7)	-	9.7	-	7 10,000

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions			Unit			
				Min.	Тур.	Max.	Onit	
Mt	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N·m	
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N·m	
d _s Creepage distance	Craanaga distance	Terminal to terminal		18.4	-	-	mm	
	Creepage distance	Terminal to base plate		21.1	-	-	111111	
d _a Clearance	Terminal to terminal		9.6	-	-	mm		
	Clearance	Terminal to base plate		16.7	1	-	111111	
m	mass	-		-	120	-	g	
ec	Flatness of base plate	On the centerline (Note8)		±0	-	+200	μm	

- *: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (DIODE).
 - 2. Junction temperature $(T_{\nu j})$ should not increase beyond $T_{\nu j \, m \, a \, x}$ rating.
 - 3. Pulse width and repetition rate should be such that the device junction temperature (Tvj) dose not exceed Tvjmax rating.
 - 4. Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
 - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
 - 6. Typical value is measured by using thermally conductive grease of λ=0.9 W/(m·K)/D_(C-S)=50 μm.
 - 7. Typical value is measured by using PC-TIM of λ =3.4 W/(m·K)/D_(C-S)=50 μ m.
 - 8. The base plate (mounting side) flatness measurement point is as follows of the following figure.



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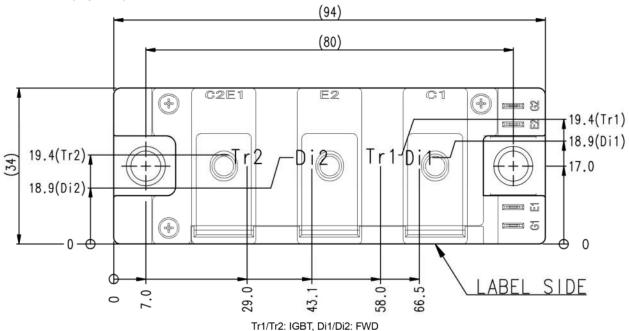


RECOMMENDED OPERATING CONDITIONS

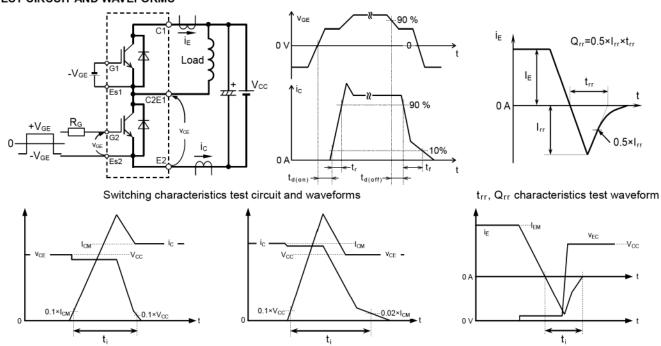
Symbol Item	Conditions	Limits			Unit	
	item	Conditions		Тур.	Max.	Offic
Vcc	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	850	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-E1s/G2-E2s terminals	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	9.1	-	91	Ω

CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm



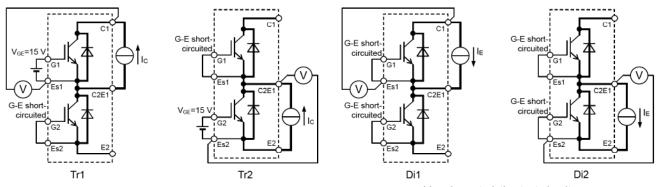
TEST CIRCUIT AND WAVEFORMS



IGBT Turn-off switching energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

TEST CIRCUIT

IGBT Turn-on switching energy



V_{EC} characteristics test circuit

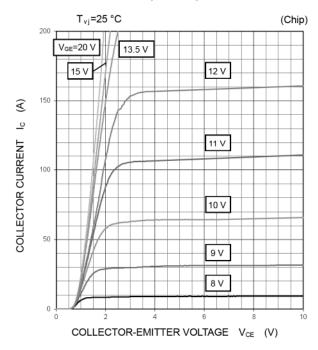
FWD Reverse recovery energy



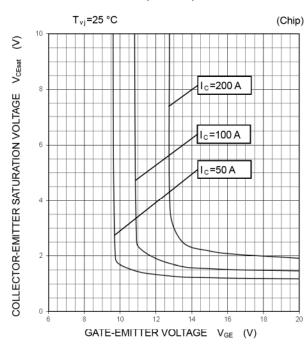
PERFORMANCE CURVES

OUTPUT CHARACTERISTICS

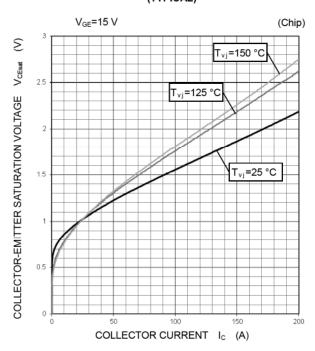
(TYPICAL)



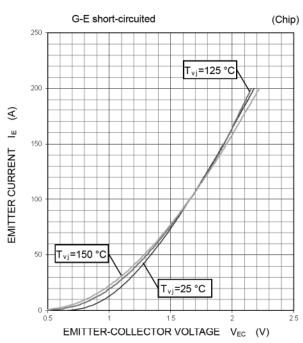
COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

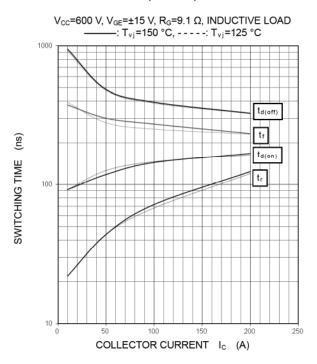


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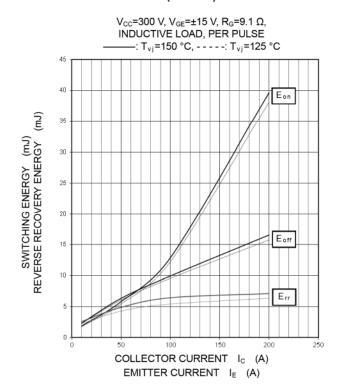


PERFORMANCE CURVES

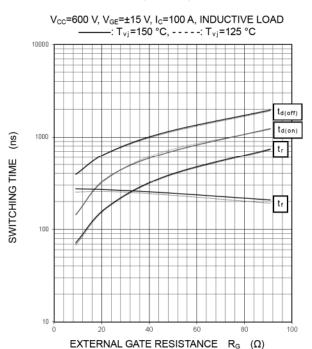
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



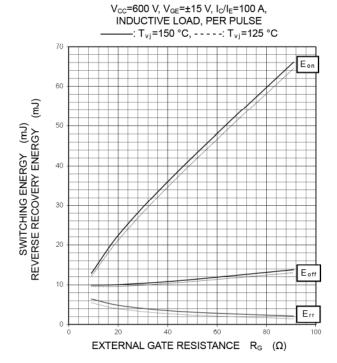
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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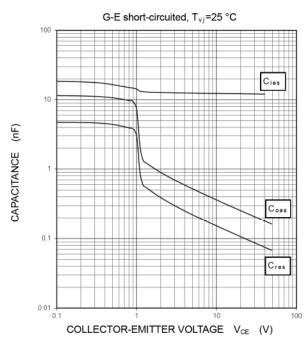




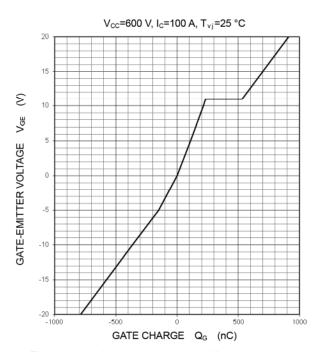
PERFORMANCE CURVES

CAPACITANCE CHARACTERISTICS

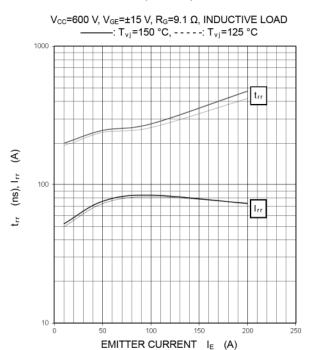
(TYPICAL)



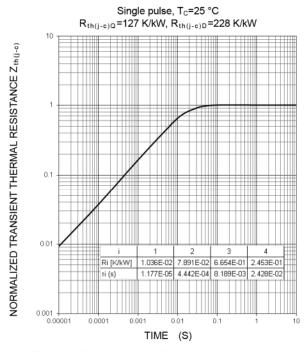
GATE CHARGE CHARACTERISTICS (TYPICAL)



FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



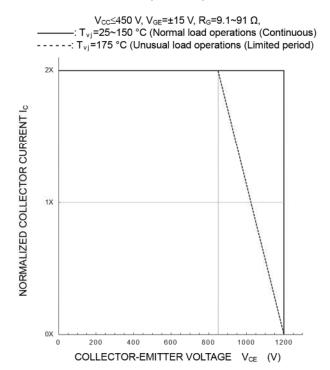
Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

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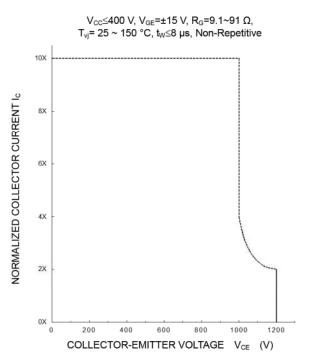


PERFORMANCE CURVES

TURN-OFF SWITCHING SAFE OPERATIONG AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)



SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)





Keep safety first in your circuit designs!

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